TOSHIBA SG1500EX24

TOSHIBA GATE TURN-OFF THYRISTOR

SG1500EX24

INVERTER APPLICATION

Repetitive Peak off-state Voltage : $V_{DRM} = 2500 \text{ V}$ (Note 1)

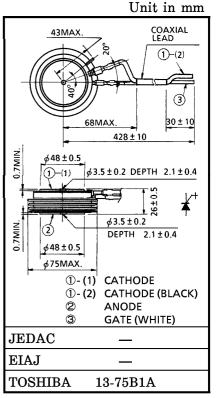
R.M.S On-State Current : $I_{T (RMS)} = 750 A$ Peak Turn-Off Current : $I_{TGQM} = 1500 A$

Critical Rate of Rise of On-State Current : $di/dt = 500 \text{ A}/\mu\text{s}$

Critical Rate of Rise of off-State Voltage : $dv/dt = 1000 \text{ V}/\mu\text{s}$

MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL RATING		UNIT	
Repetitive Peak Off-state Voltage (Note 1)	$v_{ m DRM}$	2500	V	
Repetitive Peak Reverse Voltage	v_{RRM}	16	V	
Peak Turn-Off Current (Note 2)	I_{TGQM}	1500	A	
R.M.S On-State Current (Note 3)	IT (RMS)	750	Α	
Peak One Cycle Surge On-State Current (Non Repetitive, 10 ms- Width Half Sine Waveform)	I_{TSM}	8000	A	
Critical Rate Of Rise Of On-State Current (Note 4)	di/dt	500	A/μs	
Peak Gate Current	I_{GM}	400	Α	
Average Gate Power Dissipation	PG (AV)	80	W	
R.M.S Gate Current (Note 5)	IG (RMS)	42	Α	
Peak Reverse Gate Voltage (at Static)	v_{RGM}	16	V	
Operating Junction Temperature Range	T_{j}	-40~125	°C	
Storage Temperature Range	T _{stg} -40~150		°C	
Mounting Force	_	13.7 ± 1.4	kN	



Weight: 520 g

(Note 1): $V_{GK} = -2 V$

(Note 2): $V_{DM}^{AA} \le 2000 \text{ V}$, $C_S = 3 \mu\text{F}$, $R_S = 5 \Omega$, $di_{GQ} / dt = 30 \text{ A} / \mu\text{s}$, $V_{DSP} \le 650 \text{ V}$,

 $L_S \leq 0.2 \,\mu H$

(Note 3): 50 Hz Half Sine Waveform at $T_f = 78^{\circ}\text{C}$ (Note 4): $V_D = 1250 \text{ V}, I_{GM} = 15 \text{ A}, T_j = 125^{\circ}\text{C}$

(Note 5): Ambient Temperature of coaxial gate-cathode lead = 90°C

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ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	TEST COND	MIN.	TYP.	MAX.	UNIT	
	SIMBOL	TEST CONDITION		MIIIN.	IIF.	MAA.	UNII
Repetitive Peak Off-State Current	$I_{ m DRM}$	$V_{DRM} = 2500 \text{ V}, V_{GK} = -2 \text{ V}, $ $T_j = 125^{\circ}\text{C}$		_	_	40	mA
Repetitive Peak Reverse Current	I_{RRM}	$egin{aligned} V_{\mathrm{RRM}} &= 16 \mathrm{V}, \\ T_{\mathrm{j}} &= 125 ^{\circ} \mathrm{C} \end{aligned}$		_	_	10	mA
Repetitive Peak Reverse Gate Current	I_{RGM}	$egin{aligned} \mathbf{V_{RGM}} &= 16\mathrm{V}, \\ \mathbf{T_{j}} &= 125^{\circ}\mathrm{C} \end{aligned}$		_	_	10	mA
Peak On-State Voltage	V_{TM}	$I_{TM} = 1500 \text{ A}, T_j = 125^{\circ}\text{C}$		_	_	3.0	V
Gate Trigger Voltage	v_{GT}		$T_j = -40^{\circ}C$	_	_	1.50	V
		$V_D = 24 V$,	$T_j = 25$ °C	_	_	1.00	V
Gate Trigger Current	I_{GT}	$R_{\rm L} = 0.1 \Omega$	$T_j = 0$ °C	_	_	6.0	A
			$T_j = 25$ °C	_	_	2.0	A
Turn-On Delay Time	^t d	$V_D = 1250 \text{ V},$ $di / dt = 300 \text{ A} / \mu \text{s},$		_	_	3.0	μ s
Turn-On Time	tgt	$I_{GM} = 15 \text{ A}, I_T = 1500 \text{ A}, T_j = 25^{\circ}\text{C}$		_	_	10.0	μs
Critical Rate of Rise of Off- State Voltage	dv/dt	$V_{DRM} = 1700 V,$ $T_j = 125 ^{\circ}C, V_{GK} = -2 V,$ Exponential Rise		1000	_	_	V / μs
Storage Time	t_S	$\begin{split} &I_{TGQ} = 1500 \text{ A,} \\ &V_{DM} = 2000 \text{ V, R}_S = 5 \Omega, \\ &V_D = 1250 \text{ V,} \\ &\operatorname{di}_{GQ}/\operatorname{dt} = 30 \text{A}/\mu\text{s,} \\ &- C_S = 3 \mu\text{F, V}_{DSP} \leqq 650 \text{V,} \\ &T_j = 125^\circ\text{C, L}_S \leqq 0.2 \mu\text{H} \end{split}$		_	_	20	μ s
Gate Turn-Off Time	$t_{ m gq}$				_	22	μs
Tail Time	^t tail			_	50	_	μ s
Gate Turn-Off Current	$I_{\mathbf{GQ}}$			_	400	_	A
Thermal Resistance (Junction to Fin)	R _{th (j-f)}	DC		_	_	0.028	°C/W

